## Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination
10/542,171	TANAKA ET AL.

10/542,171 Examiner

Karie O'Neill Apicella

Art Unit 1795

SEARCHED					
Class	Subclass	Date	Examiner		

Class	Subclass	Date	Examiner		
			-		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Consulted with Dah-wei Yuan Re: claim language	3/10/2010	коа		
Searched in EAST	3/10/2010	коа		
Inventor search in eDAN	3/10/2010	КОА		
Consulted with Pat Ryan Re: claim language	3/11/2010	КОА		